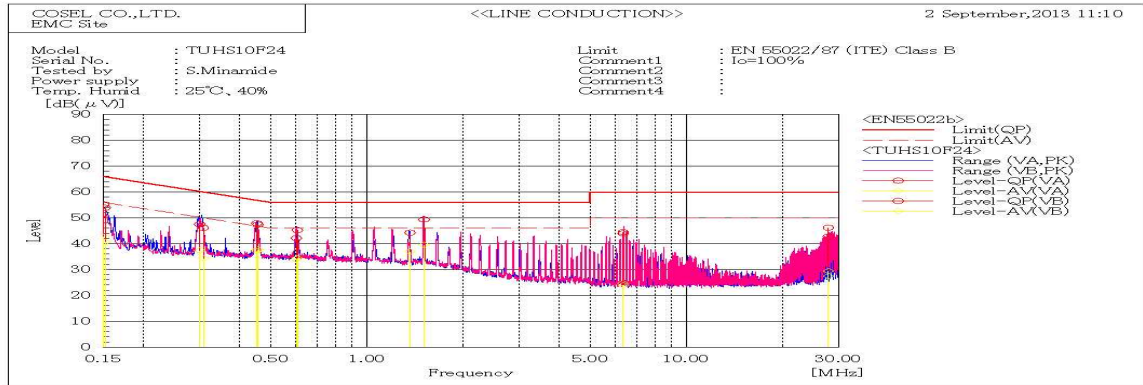
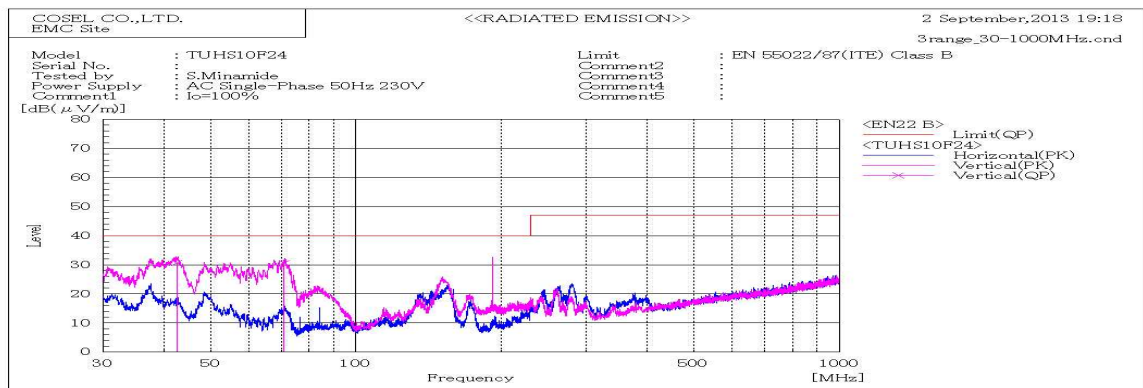


DATA SHEET		Date	16-Dec-13
Model	TUHS10F24	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Minamide



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.15197		VB	33.7	20.5	20.2	53.9	40.7	65.9	55.9	12.0	15.2	Pass	
0.15056		VA	34.9	22.3	20.3	55.2	42.6	66.0	56.0	10.8	13.4	Pass	
0.30032		VB	27.4	17.3	20.1	47.5	37.4	60.2	50.2	12.7	12.8	Pass	
0.30847		VA	26.0	14.2	20.1	46.1	34.3	60.0	50.0	13.9	15.7	Pass	
0.45343		VB	27.8	17.1	20.1	47.9	37.2	56.8	46.8	8.9	9.6	Pass	
0.45686		VA	27.3	17.6	20.1	47.4	37.7	56.7	46.7	9.3	9.0	Pass	
0.60653		VB	25.2	14.4	20.1	45.3	34.5	56.0	46.0	10.7	11.5	Pass	
0.60192		VA	22.1	13.9	20.1	42.2	34.0	56.0	46.0	13.8	12.0	Pass	
1.36684		VA	24.1	16.7	20.2	44.3	36.9	56.0	46.0	11.7	9.1	Pass	
1.51034		VB	29.2	19.3	20.2	49.4	39.5	56.0	46.0	6.6	6.5	Pass	
6.34186		VA	23.3	4.2	20.6	43.9	24.8	60.0	50.0	16.1	25.2	Pass	
6.33785		VB	23.9	3.4	20.6	44.5	24.0	60.0	50.0	15.5	26.0	Pass	
27.7658		VA	21.8	6.6	20.9	42.7	27.5	60.0	50.0	17.3	22.5	Pass	
27.78025		VB	25.2	8.5	21.0	46.2	29.5	60.0	50.0	13.8	20.5	Pass	



Frequency MHz	Polariz ation	Stabilit y	Reading dB(μV)	Factor dB(1/m)	Level dB(μV/m)	Limit dB(μV/m)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP		QP	QP	QP				
42.613	V	Stable	47.5	-16.7	30.8	40	9.2	Pass	104	46	
70.918	V	Stable	51.2	-20.6	30.6	40	9.4	Pass	120	348	

1. Line conduction



Conditions

Test: EMI

Model Name: TUHS10F□□

○ Photographs of Test Set-Up

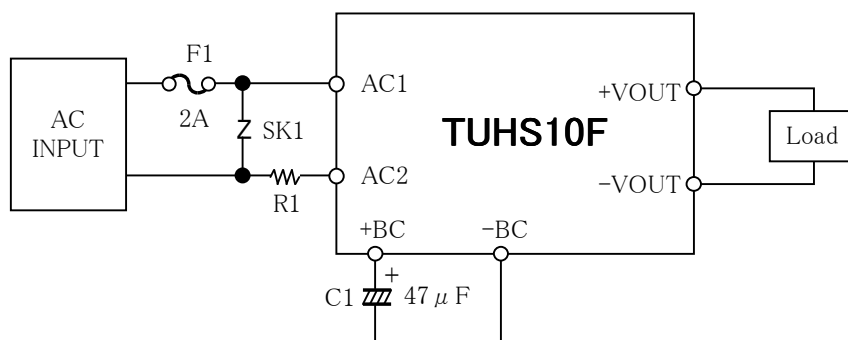
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



F1: SLT250V2A (Nippon Seisen)

R1: 2K100JA (TAMURA THERMAL DEVICE)

SK1: S10K385E2K1 (TDK EPCOS)

2A

10 Ω

Fig.1 Testing circuitry